


<b>Search Notes</b> 	<b>Application/Control No.</b> 10645699	<b>Applicant(s)/Patent Under Reexamination</b> ENKO ET AL.
	<b>Examiner</b> Myint, Dennis	<b>Art Unit</b> 2162

SEARCHED			
Class	Subclass	Date	Examiner
707	103X & 205	9/17/2008	DM
709	203	9/17/2008	DM

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (EPO; JPO; IBM; USPAT; USPGPUB)	06/06/2006	DM
EAST (EPO; JPO; IBM; USPAT; USPGPUB)	11/13/2006	DM
709/24, Limited with keywords	06/06/2006	DM
711/ 161, Limited with keywords	06/06/2006	DM
709/227, Limited with keywords	11/13/2006	DM
EAST (EPO; JPO; IBM; USPAT; USPGPUB)	07/27/2007	DM
EAST (EPO; JPO; IBM; USPAT; USPGPUB) , attached	12/17/2007	DM
PALM Inventor search	12/17/2007	DM
NPL: ACM database search , attached	12/17/2007	DM
NPL: IEEE database search , attached	12/17/2007	DM
NPL: Google Scholar search , attached	12/17/2007	DM
707/10, limited with keywords , attached	12/17/2007	DM
EAST (EPO; JPO; IBM; USPAT; USPGPUB) , attached	4/24/2008	DM
EAST (EPO; JPO; IBM; USPAT; USPGPUB) , attached	4/25/2008	DM
NPL: Google Scholar search , attached	4/24/2008	DM
NPL: Google Scholar search , attached	4/25/2008	DM
NPL: ACM database search , attached	4/25/2008	DM
NPL: IEEE database search , attached	4/25/2008	DM
EAST (EPO; JPO; IBM; USPAT; USPGPUB) , attached	9/17/2008	DM
NPL: Google Scholar search , attached	9/17/2008	DM
NPL: ACM database search , attached	9/17/2008	DM
NPL: IEEE database search , attached	9/17/2008	DM
Consulted with SPRE Vincent Tran for 35 U.S.C. 101 for claim 1	9/23/2008	DM

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	EAST (US-PGPUB, USPAT) keywords.clm	9/17/2008	DM

/DENNIS MYINT/  
Examiner, Art Unit 2162

**INTERFERENCE SEARCH**

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
707	103X	9/17/2008	DM
709	203	9/17/2008	DM

/DENNIS MYINT/  
Examiner,Art Unit 2162